

SANYO Semiconductors DATA SHEET

3LP02M-

P-Channel Silicon MOSFET

General-Purpose Switching Device Applications

Features

- · Low ON-resistance.
- · High-speed switching.
- 2.5V drive.

Specifications

Absolute Maximum Ratings at Ta=25°C

Parameter	Symbol	Conditions	Ratings	Unit
Drain-to-Source Voltage	VDSS		-30	V
Gate-to-Source Voltage	VGSS		±10	V
Drain Current (DC)	ID		-0.2	Α
Drain Current (Pulse)	IDP	PW≤10μs, duty cycle≤1%	-0.8	Α
Allowable Power Dissipation	PD		0.15	W
Channel Temperature	Tch		150	°C
Storage Temperature	Tstg		-55 to +150	°C

Electrical Characteristics at Ta=25°C

Parameter	Symbol	Conditions	Ratings			Linit
			min	typ	max	Unit
Drain-to-Source Breakdown Voltage	V(BR)DSS	ID=-1mA, VGS=0V	-30			V
Zero-Gate Voltage Drain Current	IDSS	VDS=-30V, VGS=0V			-1	μΑ
Gate-to-Sourse Leakage Current	IGSS	VGS=±8V, VDS=0V			±10	μΑ
Cutoff Voltage	Vgs(off)	V _{DS} =-10V, I _D =-100μA	-0.4		-1.4	V
Forward Transfer Admittance	yfs	V _{DS} =-10V, I _D =-100mA	0.21	0.3		S
Static Drain-to-Source On-State Resistance	RDS(on)1	ID=-100mA, VGS=-4V		2.4	3.1	Ω
	R _{DS} (on)2	I _D =-50mA, V _G S=-2.5V		3.5	4.9	Ω
	RDS(on)3	ID=-10mA, VGS=-1.5V		10	20	Ω
Input Capacitance	Ciss	V _{DS} =-10V, f=1MHz		28		pF
Output Capacitance	Coss	V _{DS} =-10V, f=1MHz		15		pF
Reverse Transfer Capacitance	Crss	V _{DS} =-10V, f=1MHz		5.2		pF
Turn-ON Delay Time	t _d (on)	See specified Test Circuit.		24		ns
Rise Time	t _r	See specified Test Circuit.		75		ns
Turn-OFF Delay Time	td(off)	See specified Test Circuit.		200		ns
Fall Time	tf	See specified Test Circuit.		150		ns

Marking: XD Continued on next page.

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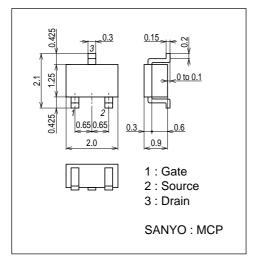
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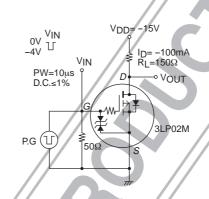
Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	Offic
Total Gate Charge	Qg	VDS=-10V, VGS=-10V, ID=-200mA		2		nC
Gate-to-Source Charge	Qgs	V _{DS} =-10V, V _{GS} =-10V, I _D =-200mA		0.25		nC
Gate-to-Drain "Miller" Charge	Qgd	VDS=-10V, VGS=-10V, ID=-200mA		0.35		nC
Diode Forward Voltage	VSD	IS=-200mA, VGS=0V		-0.82	-1.2	V

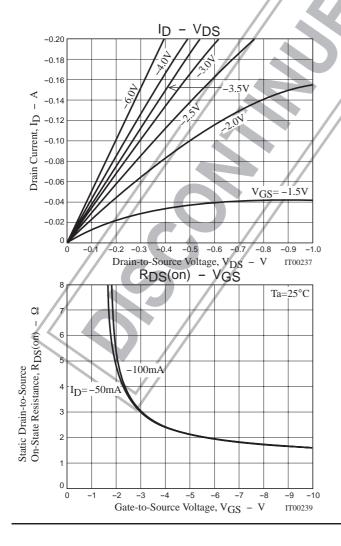
Package Dimensions

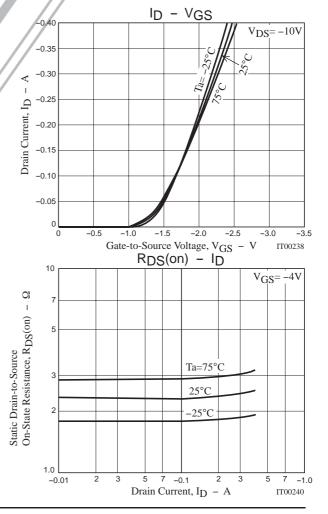
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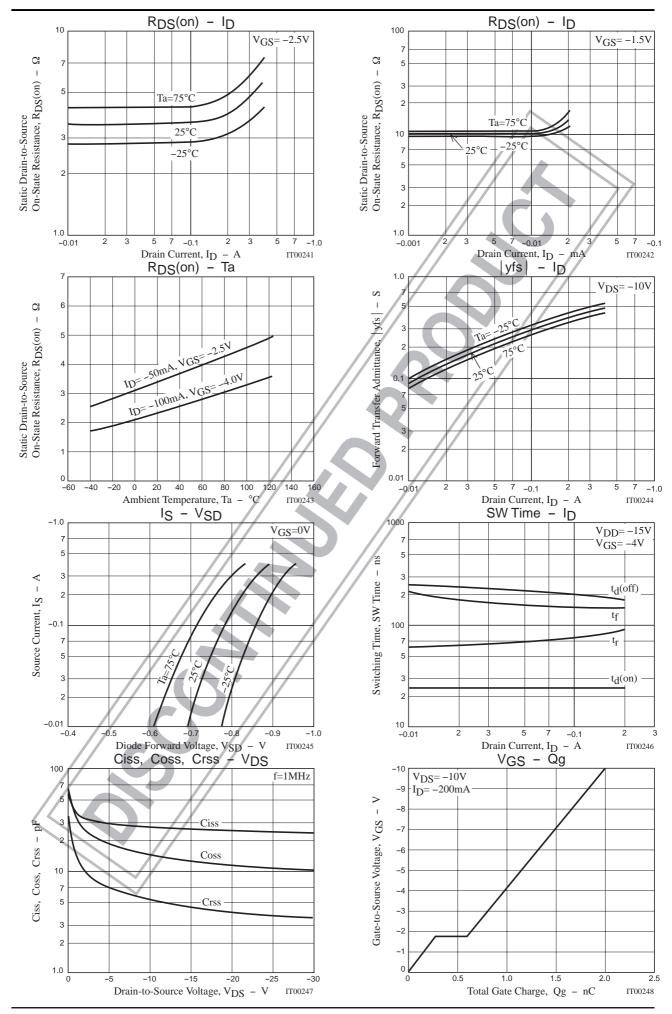


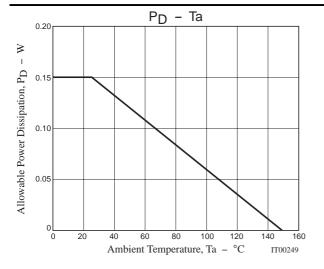
Switching Time Test Circuit













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